

<b>Notice of References Cited</b>	Application/Control No. 10/652,653	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
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**VIET Q. NGUYEN**  
**PRIMARY EXAMINER**

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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